

<b>Notice of References Cited</b>	Application/Control No. 09/732,712	Applicant(s)/Patent Under Reexamination ITOU ET AL.	
	Examiner Yelena G. Gakh, Ph.D.	Art Unit 1743	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,075,306	02-1978	Muromura, Tadasumi	423/352
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Girard et al. "PPB-Level Hydrometry in Nitrogen and ESG's Using Tunable Diode Laser Spectroscopy", The International Symposium on Semiconductor Manufacturing, October 1996, pp. 325-328
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.